

Amendments to the Claims

The following listing of claims will replace all prior versions and/or listings of claims in the application:

1. (Currently amended): A probe coming into contact with an electrode pad of a measurement object, comprising:

a connection terminal part integrally formed and connected to a substrate;

a probe support portion; and

a contact part, the contact part comprising

an edge part part-having a tapered end configuration; and

a supporting-partcontact support part which supports the contact partedge part and couples the edge part to the probe support part,

wherein the contact part extending-extends from an end of the the probe supporting partsupport part, and wherein the edge part has a sectional configuration which shares at least one side face with the supporting-partcontact support part and wherein the edge part has a thickness that is less than the thickness of the contact support part.

2. (Original): The probe according to claim 1, wherein the contact part is formed of an electrically conductive material having superior electric characteristics.

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3. (Original): The probe according to claim 1, wherein the contact part is formed of a metal material having elasticity.